

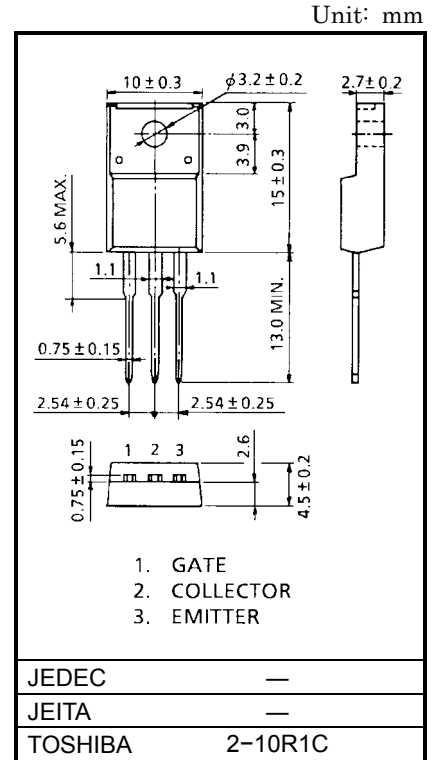
# GT15G101

## STROBE FLASH APPLICATIONS

- High Input Impedance
- Low Saturation Voltage :  $V_{CE(sat)} = 8V$  (Max.) ( $I_C = 170A$ )
- Enhancement-Mode
- 20V Gate Drive

## MAXIMUM RATINGS ( $T_a = 25^\circ C$ )

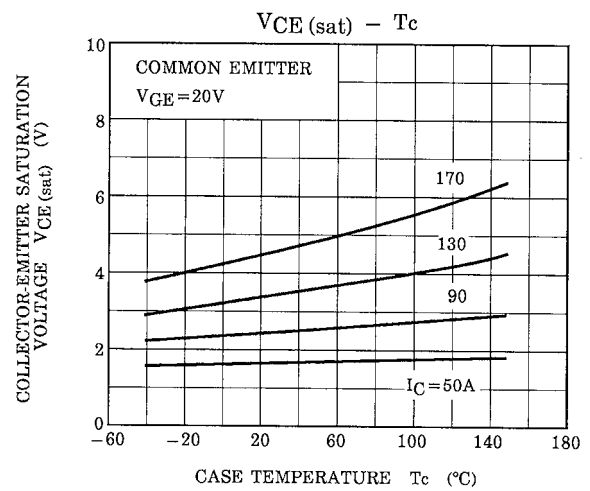
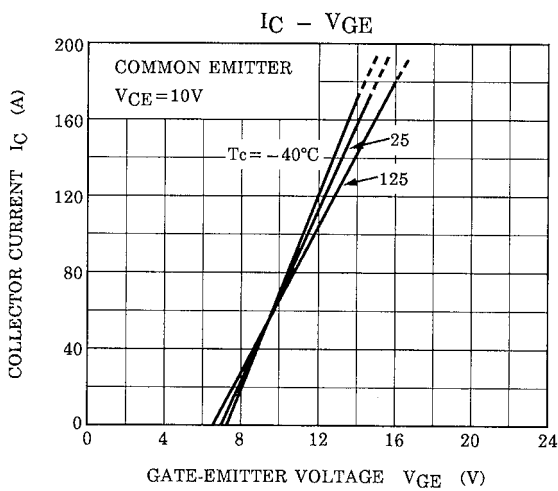
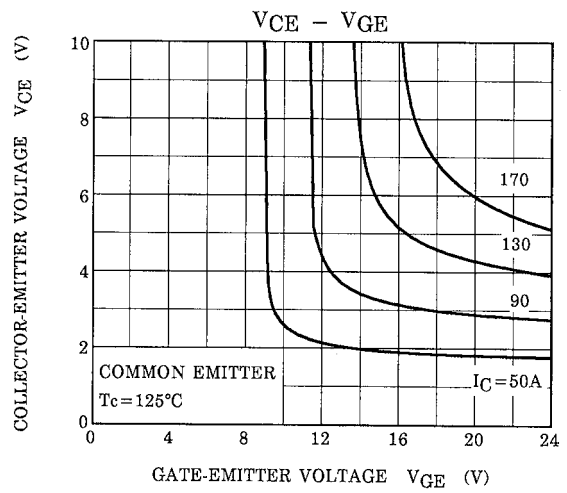
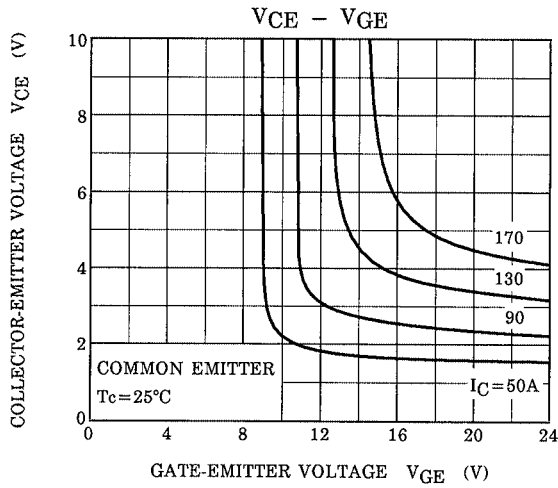
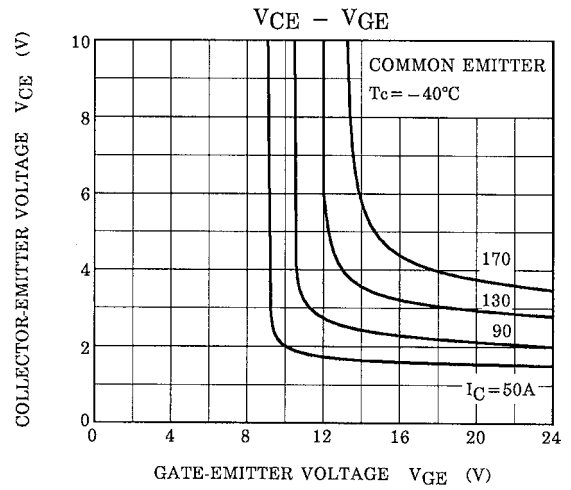
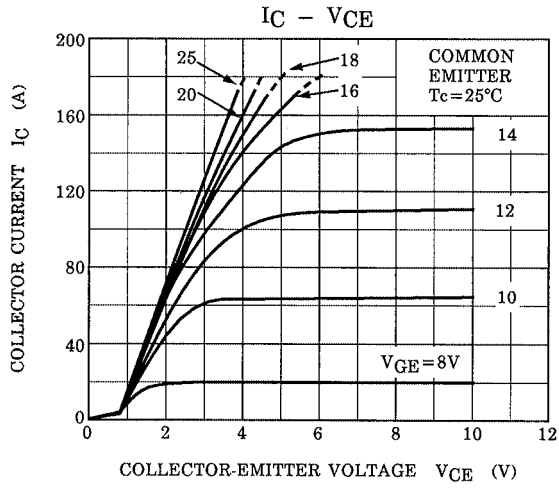
CHARACTERISTIC		SYMBOL	RATING	UNIT
Collector-Emitter Voltage		$V_{CES}$	400	V
Gate-Emitter Voltage		$V_{GES}$	$\pm 25$	V
Collector Current	DC	$I_C$	15	A
	1ms	$I_{CP}$	170	
Collector Power Dissipation	$T_a = 25^\circ C$	$P_C$	2.0	W
	$T_c = 25^\circ C$	$P_C$	40	
Junction Temperature		$T_j$	150	$^\circ C$
Storage Temperature Range		$T_{stg}$	-55~150	$^\circ C$
Screw Torque		—	0.6	N · m

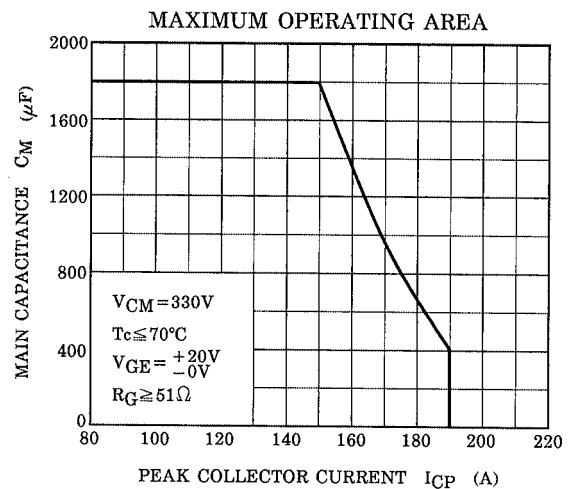
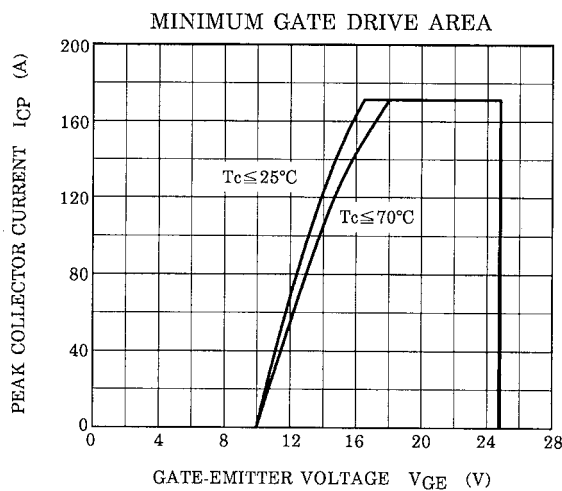
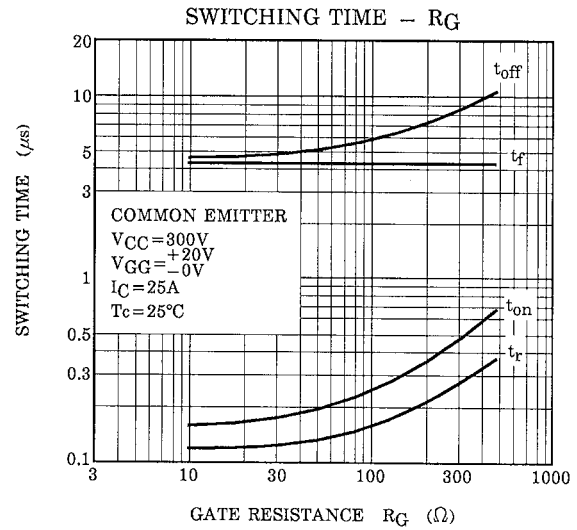
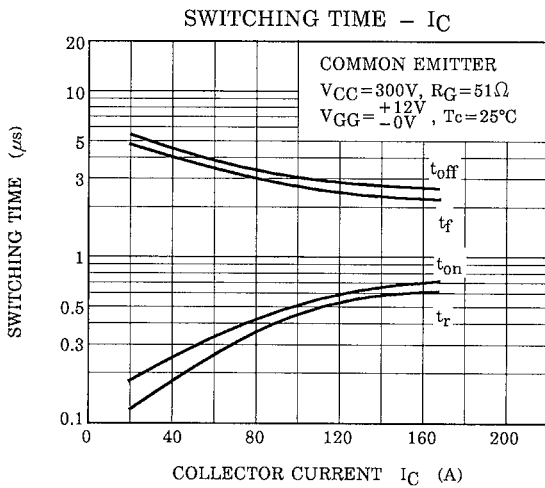
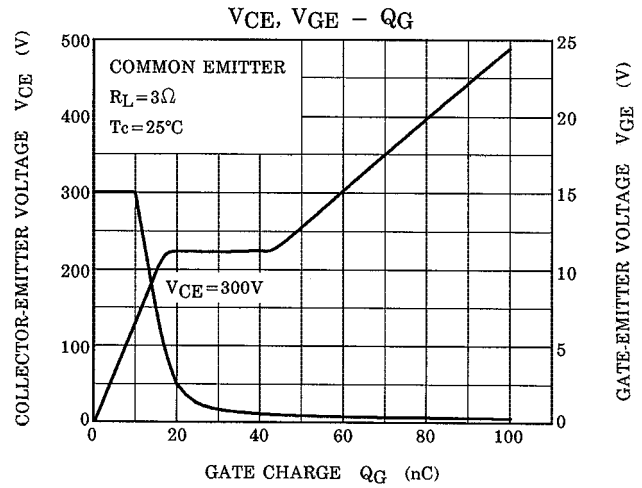
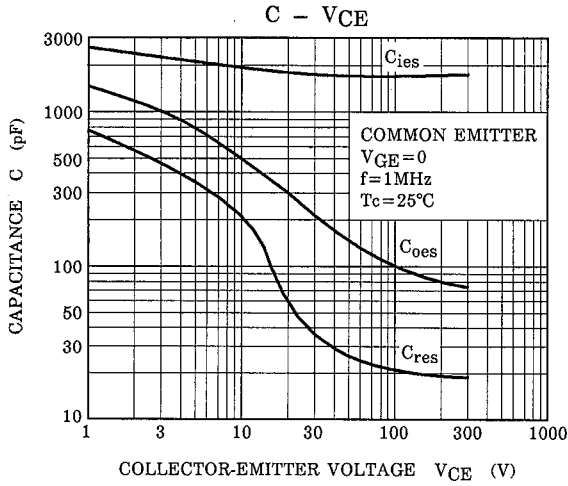


Weight: 1.7g

## ELECTRICAL CHARACTERISTICS ( $T_a = 25^\circ C$ )

CHARACTERISTIC		SYMBOL	TEST CONDITION	MIN	TYP.	MAX	UNIT
Gate Leakage Current		$I_{GES}$	$V_{GE} = \pm 25V, V_{CE} = 0$	—	—	$\pm 100$	nA
Collector Cut-off Current		$I_{CES}$	$V_{CE} = 400V, V_{GE} = 0$	—	—	10	$\mu A$
Gate-Emitter Cut-off Voltage		$V_{GE(OFF)}$	$I_C = 1mA, V_{CE} = 5V$	4	5	7	V
Collector-Emitter Saturation Voltage		$V_{CE(sat)}$	$I_C = 170A, V_{GE} = 20V$ (Pulsed)	—	5	8	V
Input Capacitance		$C_{ies}$	$V_{CE} = 10V, V_{GE} = 0, f = 1MHz$	—	2000	—	pF
Switching Time	Rise Time	$t_r$	 $V_{IN} : t_r \leq 100ns$ $t_f \leq 100ns$ Duty cycle $\leq 1\%$	—	0.1	0.5	$\mu s$
	Turn-on Time	$t_{on}$		—	0.15	0.5	
	Fall Time	$t_f$		—	4.0	6.0	
	Turn-off Time	$t_{off}$		—	4.5	7.0	
Thermal Resistance		$R_{th(j-c)}$	—	—	—	3.12	$^\circ C / W$





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